

Information Disclosure Statement
USSN 10/627,405
February 7, 2005
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Form PTO-1449 (Modified)	ATTY DOCKET NO. B-5025NP 620801.2	U.S. SERIAL NO. 10/627,405
LIST OF PATENTS AND PUBLICATIONS STATEMENT	APPLICANTS André DeHon, et al.	
	FILING DATE July 24, 2003	GROUP 2817

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUBCLASS	FILING DATE OR 102(e) DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	ISSUE DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO

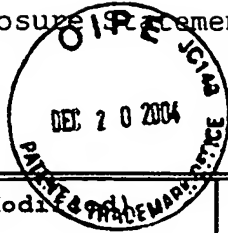
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

SWC	DeHon, A., "Array-Based Architecture for FET-Based, Nanoscale Electronics," IEEE Transactions on Nanotechnology, Vol. 2, No. 1, pp. 23-32 (March 2003).
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EXAMINER	DATE CONSIDERED
CRANE	2/2005

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Information Disclosure Statement
 USSN 10/627,405
 December 14, 2004
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUB- CLASS	FILING DATE or 102(e) DATE IF APPROPRIATE
SWC	6,383,784 B1	5/2002	Smith	435	91.2	
SWC	2002/0027819 A1	3/2002	Tomanek et al.	365	215	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	ISSUE DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO
SWC	02/103753 A2	12/2002	WO			
SWC	2004/034467 A2	4/2004	WO			
SWC	2004/061859 A2	7/2004	WO			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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